

DCR3650Y28

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Phase Control Thyristor

Preliminary Information

DS5875-1.2 September 2007 (LN25542)

FEATURES

- Double Side Cooling
- High Surge Capability

APPLICATIONS

- High Power Drives
- High Voltage Power Supplies
- Static Switches

VOLTAGE RATINGS

Part and Ordering Number	Repetitive Peak Voltages V _{DRM} and V _{RRM} V	Conditions
DCR3650Y28 DCR3650Y26 DCR3650Y24	2800 2600 2400	$ \begin{split} T_{vj} &= -40 ^\circ \!\! C \text{ to } 125 ^\circ \!\! C, \\ I_{ORM} &= I_{RRM} = 200 \text{mA}, \\ V_{DRM}, V_{RRM} t_p &= 10 \text{ms}, \\ V_{DSM} \& V_{RSM} &= \\ V_{DRM} \& V_{RRM} + 100 V \\ respectively \end{split} $

Lower voltage grades available.

ORDERING INFORMATION

When ordering, select the required part number shown in the Voltage Ratings selection table.

For example:

DCR3650Y28

Note: Please use the complete part number when ordering and quote this number in any future correspondence relating to your order.

KEY PARAMETERS

V _{DRM}	2800V
I _{T(AV)}	3650A
ITSM	50500A
dV/dt*	1500V/μs
dl/dt	300A/μs
dl/dt	300A/μs

* Higher dV/dt selections available

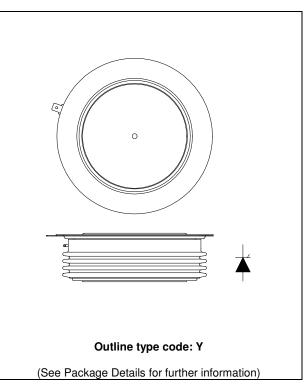


Fig. 1 Package outline

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CURRENT RATINGS

 T_{case} = 60 $^{\circ}\!C$ unless stated otherwise

Symbol	Parameter	Test Conditions	Max.	Units
Double Sid	de Cooled			
I _{T(AV)}	Mean on-state current	Half wave resistive load	3650	А
I _{T(RMS)}	RMS value	-	5730	А
Ι _Τ	Continuous (direct) on-state current	-	5105	А

SURGE RATINGS

Symbol	Parameter	Parameter Test Conditions			
I _{TSM}	Surge (non-repetitive) on-state current	10ms half sine, $T_{case} = 125 ^{\circ}C$	50.5	kA	
l ² t	I ² t for fusing	V _R = 0	12.74	MA ² s	

THERMAL AND MECHANICAL RATINGS

Symbol	Parameter	Test Condition	Min.	Max.	Units	
R _{th(j-c)}	Thermal resistance – junction to case	Double side cooled DC		-	0.00835	℃/W
		Single side cooled	Anode DC	-	0.0134	°C/W
			Cathode DC	-	0.023	°C/W
R _{th(c-h)}	Thermal resistance – case to heatsink	Clamping force 54kN Double side		-	0.002	°C/W
		(with mounting compound)	Single side	-	0.004	°C/W
T_{vj}	Virtual junction temperature	On-state (conducting)		-	135	Ŝ
		Reverse (blocking)		-	125	S
T _{stg}	Storage temperature range			-55	125	°C
Fm	Clamping force			48.0	59.0	kN



DYNAMIC CHARACTERISTICS

Symbol	Parameter	Test Conditio	Min.	Max.	Units	
I _{RRM} /I _{DRM}	Peak reverse and off-state current	At V _{RRM} /V _{DRM} , T _{case} = 125 °C	-	200	mA	
dV/dt	Max. linear rate of rise of off-state voltage	To 67% V _{DRM} , T _j = 125℃, ga	ate open	-	1500	V/µs
dl/dt	Rate of rise of on-state current	From 67% V_{DRM} to 2x $I_{\text{T}(\text{AV})}$	Repetitive 50Hz	-	150	A/µs
		Gate source 30V, 10Ω,	Non-repetitive	-	300	A/µs
		$t_r < 0.5 \mu s, T_j = 125^\circ\!C$				
V _{T(TO)}	Threshold voltage – Low level	500A to 2500A at $T_{case} = 125$	5°C	-	0.8	V
	Threshold voltage – High level	2500A to 7200A at $T_{case} = 12$	-	0.95	V	
r⊤	On-state slope resistance – Low level	500A to 2500A at T _{case} = 125 ℃			0.1714	mΩ
	On-state slope resistance – High level	2500A to 7200A at T _{case} = 125 ℃			0.1114	mΩ
t _{gd}	Delay time	$V_D = 67\% V_{DRM}$, gate source 30V, 10 Ω		TBD	TBD	μs
		$t_r=0.5\mu s,T_j=25^\circ\!\!C$				
tq	Turn-off time	$T_j = 125 ^{\circ}C, V_R = 200V, dI/dt$	100	250	μs	
		$dV_{DR}/dt = 20V/\mu s$ linear				
Qs	Stored charge	I _T = 2000A, T _j = 125 ℃, dl/dt	630	1800	μC	
ΙL	Latching current	$T_j = 25 ^{\circ}\text{C}, V_D = 5V$	-	3	А	
Ι _Η	Holding current	T _j = 25 ℃, R _{G-K} = ∞, I _{TM} = 500A, I _T = 5A			300	mA



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GATE TRIGGER CHARACTERISTICS AND RATINGS

Symbol	Parameter	Test Conditions	Max.	Units
V _{GT}	Gate trigger voltage	$V_{DRM} = 5V, T_{case} = 25 ^{\circ}C$	1.5	V
V_{GD}	Gate non-trigger voltage	At V _{DRM,} T _{case} = 125 °C	TBD	V
I _{GT}	Gate trigger current	V _{DRM} = 5V, T _{case} = 25℃	250	mA
I _{GD}	Gate non-trigger current	V _{DRM} = 5V, T _{case} = 25℃	TBD	mA

CURVES

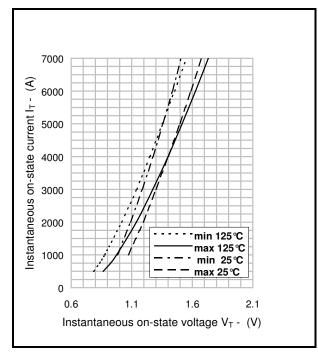


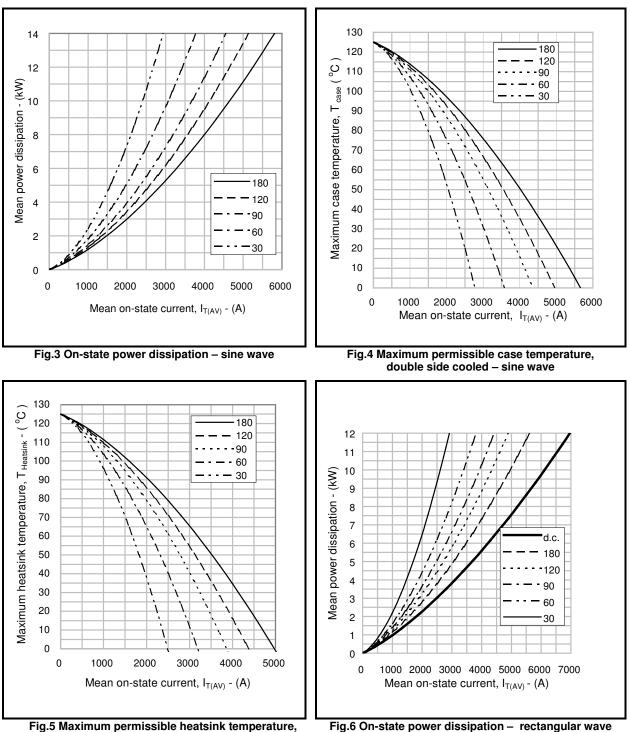
Fig.2 Maximum & minimum on-state characteristics

V_{TM} EQUATION

 $V_{TM} = A + BIn (I_T) + C.I_T + D.\sqrt{I_T}$

Where A = 0.566974 B = 0.019159 C = 0.000059 D = 0.006897 these values are valid for T_j = 125 °C for I_T 100A to 7200A

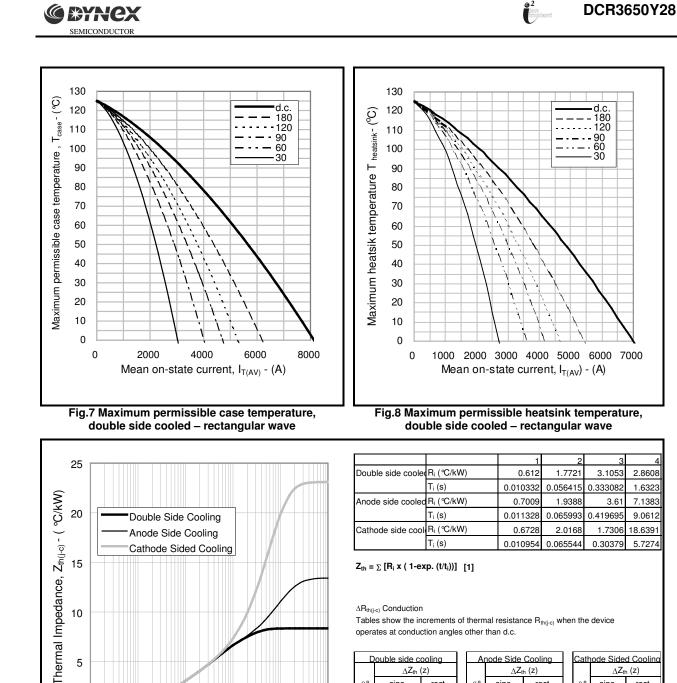




double side cooled - sine wave

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6/10

10

5

0 0.001

0.01

0.1

1

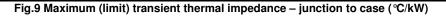
Time (s)

10

 $\Delta R_{th(j\text{-}c)} \text{ Conduction}$ Tables show the increments of thermal resistance $R_{th(j-c)}$ when the device

operates at conduction angles other than d.c.

D	ouble side cooling			Double side cooling			Anode Side Cooling			Cathode Sided Cooling			
	ΔZ_{th}	∆Z _{th} (z)		∆Z _{th} (z)				ΔZ_t	_h (z)				
θ°	sine.	rect.		θ°	sine.	rect.		θ°	sine.	rect.			
180	0.94	0.65		180	0.94	0.64		180	0.94	0.64			
120	1.09	0.92		120	1.08	0.91		120	1.08	0.91			
90	1.24	1.07		90	1.23	1.06		90	1.24	1.06			
60	1.38	1.23		60	1.37	1.22		60	1.37	1.22			
30	1.49	1.40		30	1.47	1.38		30	1.48	1.39			
15	1.54	1.49		15	1.52	1.47		15	1.53	1.48			



100

2.8608

1.6323

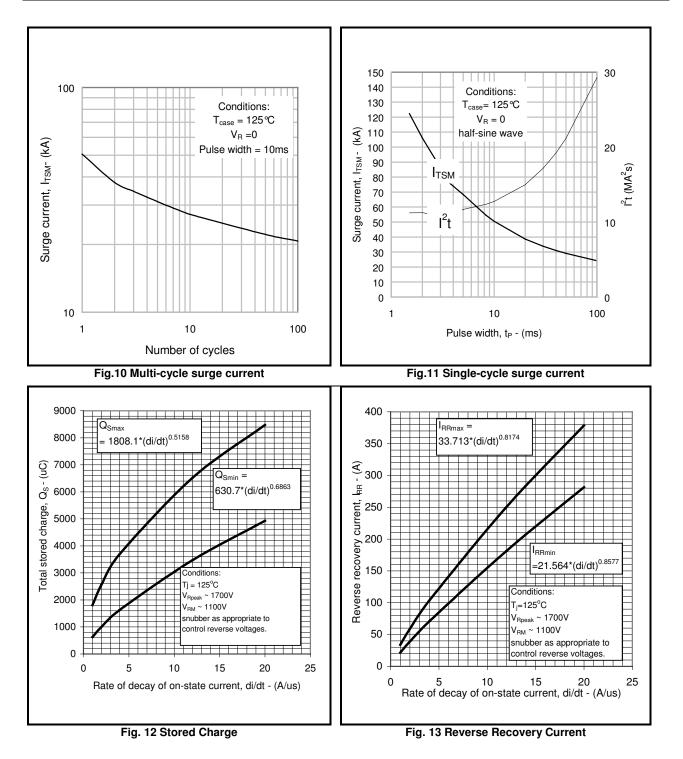
7.1383

9.0612

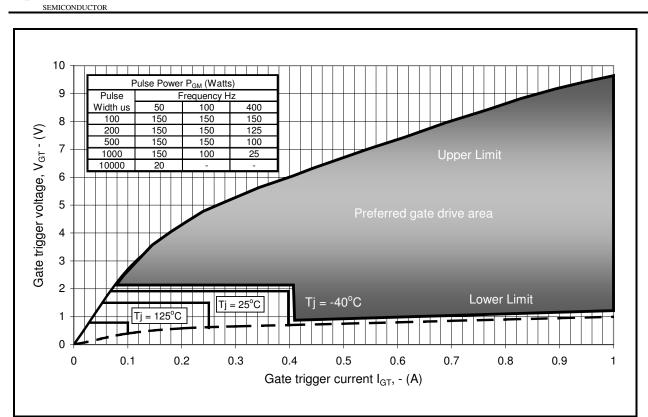
18.6391

5.7274





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Fig14 Gate Characteristics

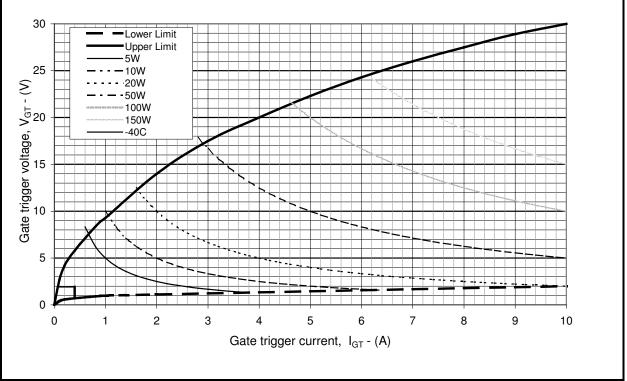


Fig. 15 Gate characteristics

@ BYNCX



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PACKAGE DETAILS

For further package information, please contact Customer Services. All dimensions in mm, unless stated otherwise. DO NOT SCALE.

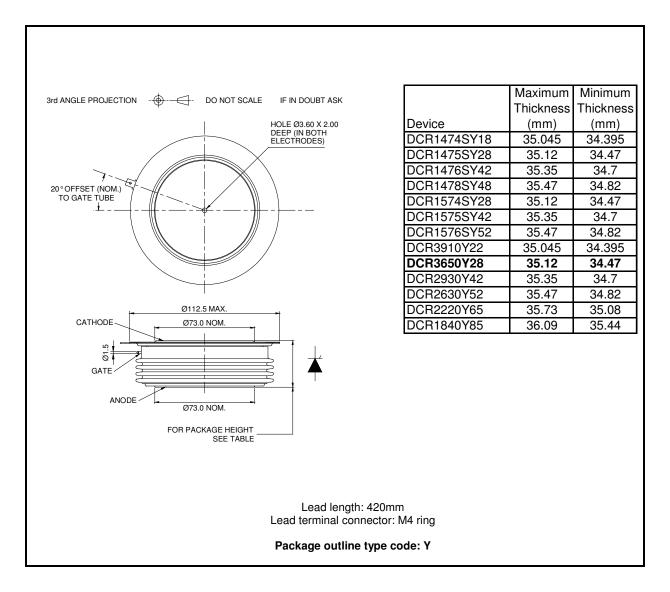


Fig.16 Package outline



POWER ASSEMBLY CAPABILITY

The Power Assembly group was set up to provide a support service for those customers requiring more than the basic semiconductor, and has developed a flexible range of heatsink and clamping systems in line with advances in device voltages and current capability of our semiconductors.

We offer an extensive range of air and liquid cooled assemblies covering the full range of circuit designs in general use today. The Assembly group offers high quality engineering support dedicated to designing new units to satisfy the growing needs of our customers.

Using the latest CAD methods our team of design and applications engineers aim to provide the Power Assembly Complete Solution (PACs).

HEATSINKS

The Power Assembly group has its own proprietary range of extruded aluminium heatsinks which have been designed to optimise the performance of Dynex semiconductors. Data with respect to air natural, forced air and liquid cooling (with flow rates) is available on request.

For further information on device clamps, heatsinks and assemblies, please contact your nearest sales representative or Customer Services.

Stresses above those listed in this data sheet may cause permanent damage to the device. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture of the package. Appropriate safety precautions should always be followed.



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